

SOLEIL Power Supply Reliability

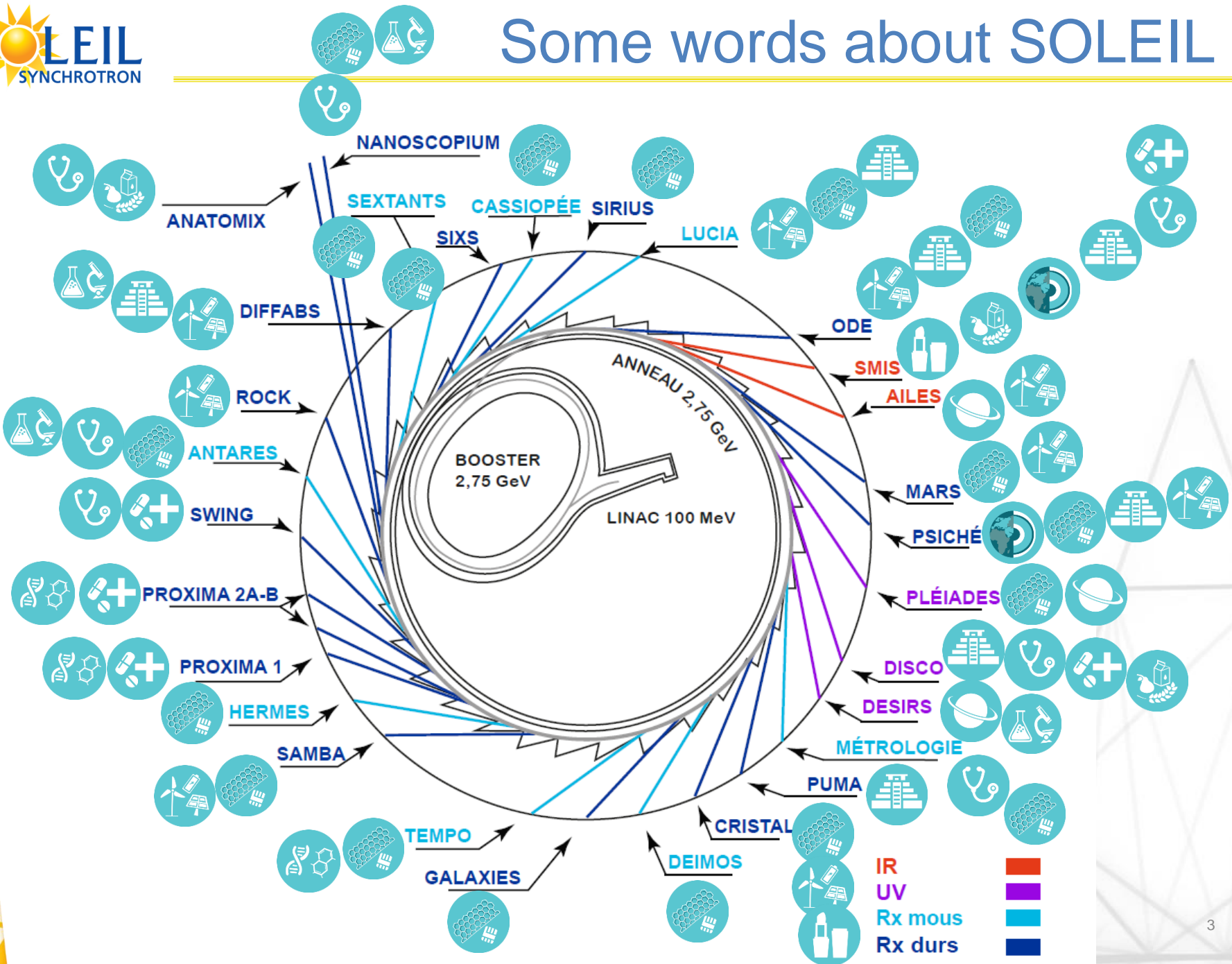
POCPA Workshop 2023

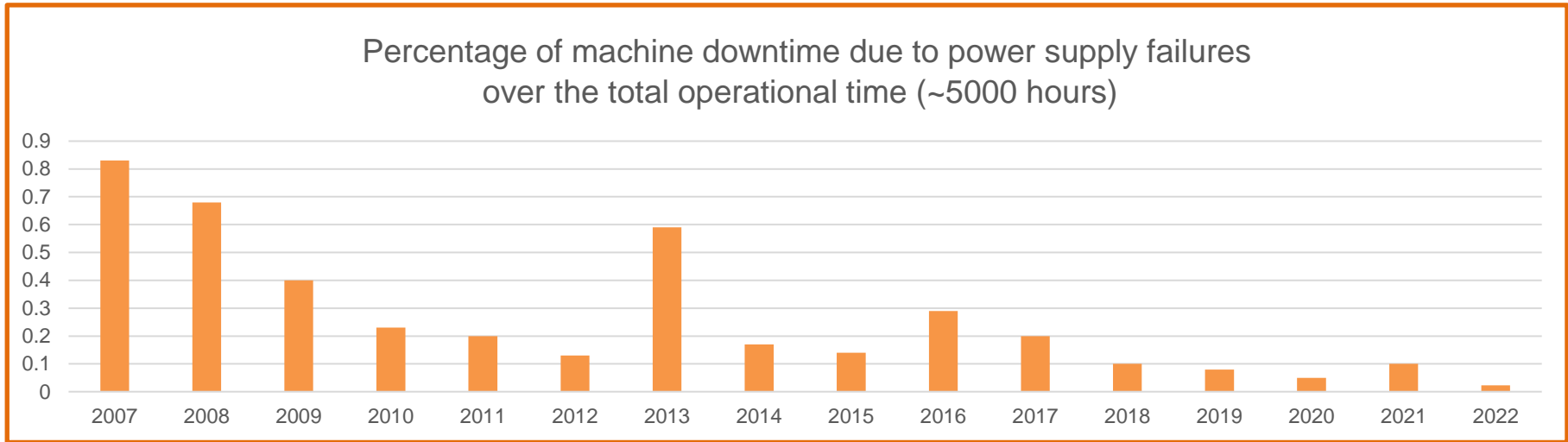
François Bouvet



- **SOLEIL:** French synchrotron light source located on the Plateau de Saclay, in Saint Aubin, Essonne
- 353 permanent staff
- 2,75 GeV storage ring ; 354 m circumference ; 500 mA stored beam
- 5000 hours of beam delivered every year to the 29 beamlines
- Wide spectral range: From infrared to hard X-rays
- 6 MW electricity consumption
- 600 magnet power supplies

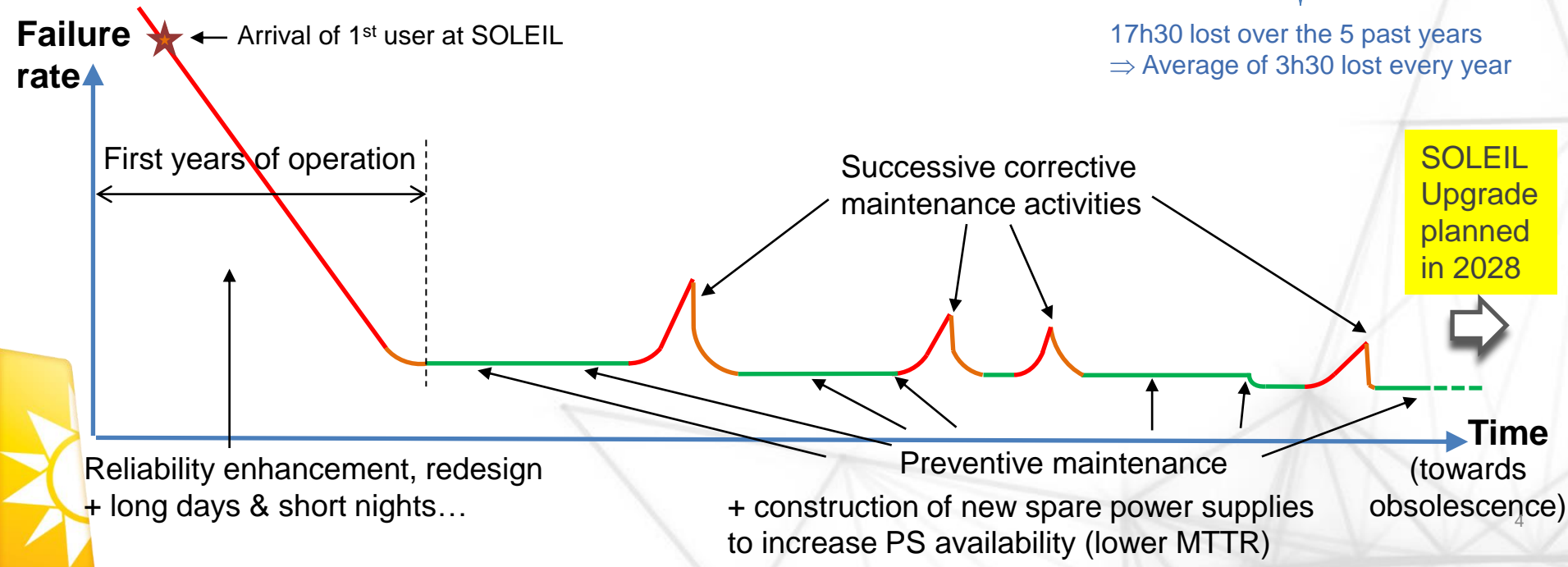
Some words about SOLEIL





17h30 lost over the 5 past years
 ⇒ Average of 3h30 lost every year

SOLEIL Upgrade planned in 2028



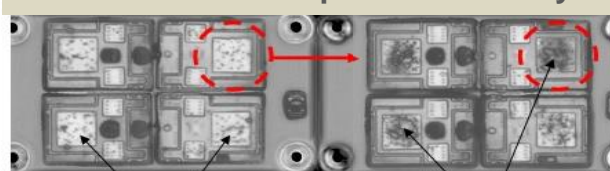
- **3Hz Booster Power supplies:** Many failures between 2007 and 2013



- SOLEIL Booster PS: About 10 Million 3Hz cycles every year
- High thermal stress caused by the 3Hz excursion of the IGBT chip's junction temperature \Rightarrow **Accelerated ageing of the IGBT modules**

Lifetime < 3 years !

Delamination of chip – substrate layer

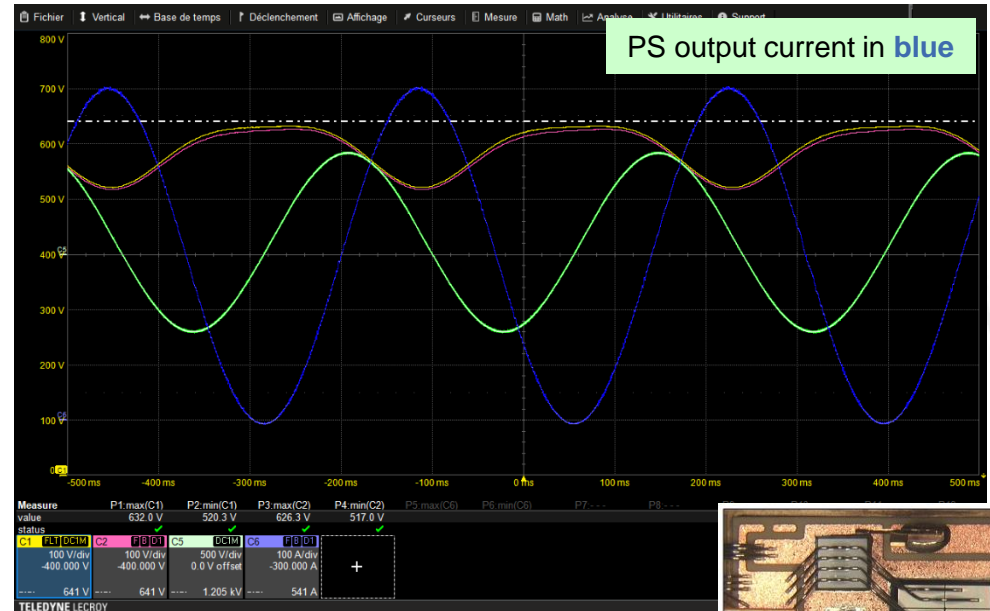


New module

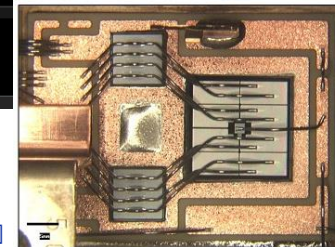
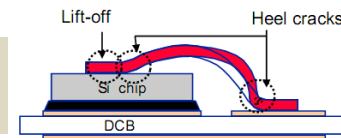
25 Million cycles

Puces IGBT

Evolution de la brasure



Bonding wire pull test on IGBT chip



New module

5 Million cycles

25 Million cycles

REF

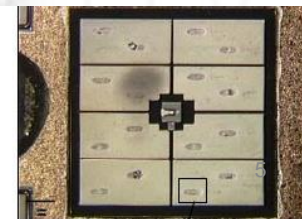
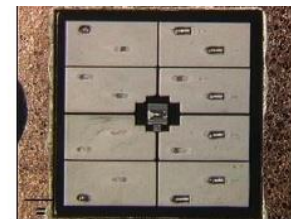
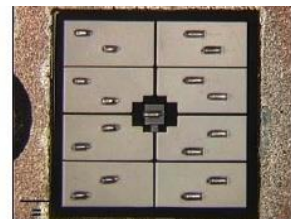
SN003

SN010

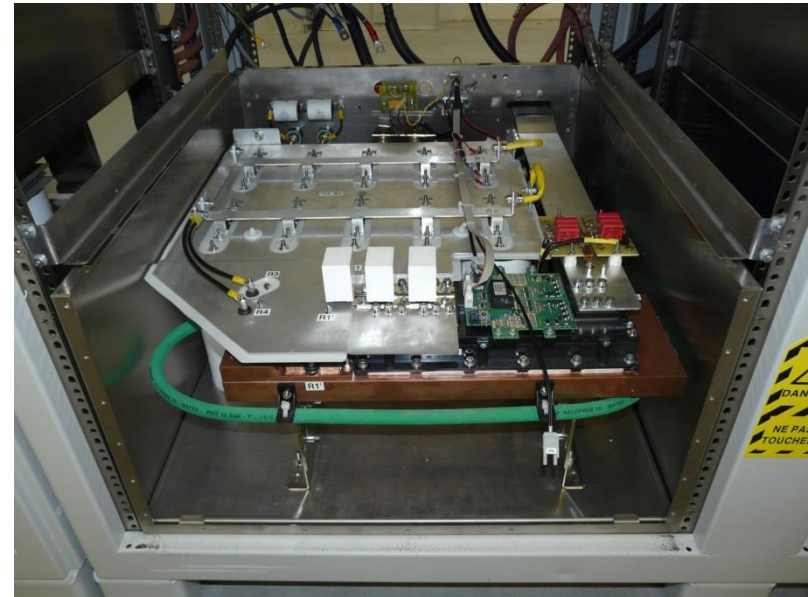
(Wedge arraché : 0/64)

(Wedges arrachés : 43/64)

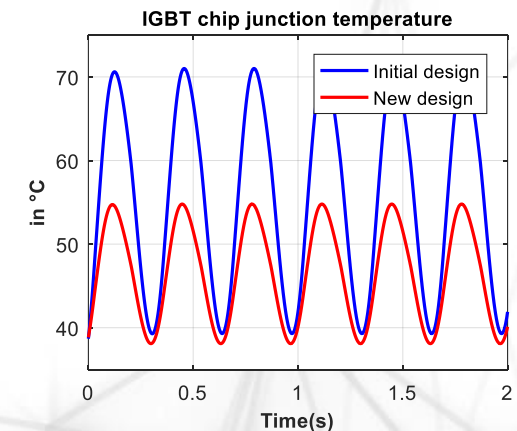
(Wedges arrachés : 60/64)



- **3Hz Booster Power supplies:** Complete redesign of the power crates in 2013

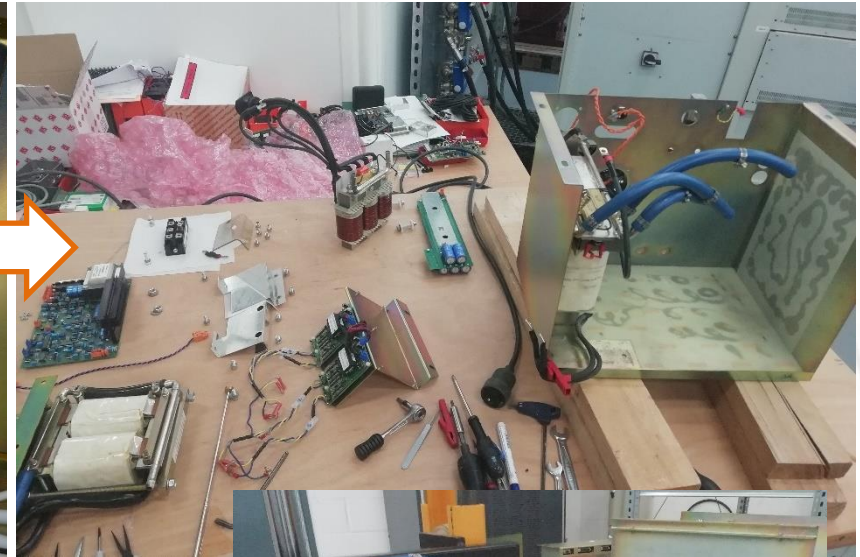
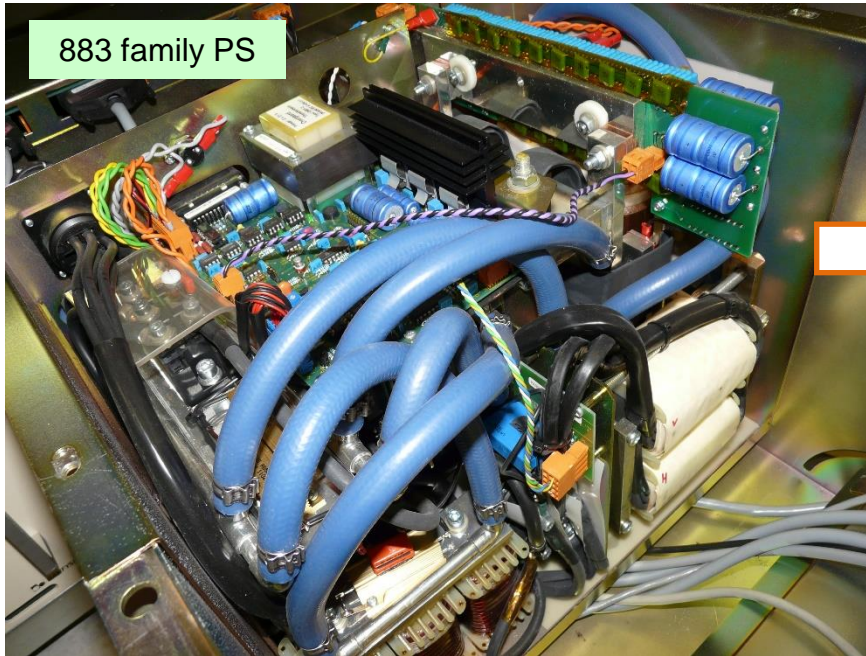


New crates based on 1200V / 2500A IGBT modules with high thermal / power cycling capability
 Calculation of IGBT junction temperature excursion: $\sim 17^{\circ}\text{C}$
Estimation of the IGBT cycling capability:
> 200 Million
No failure since 2014



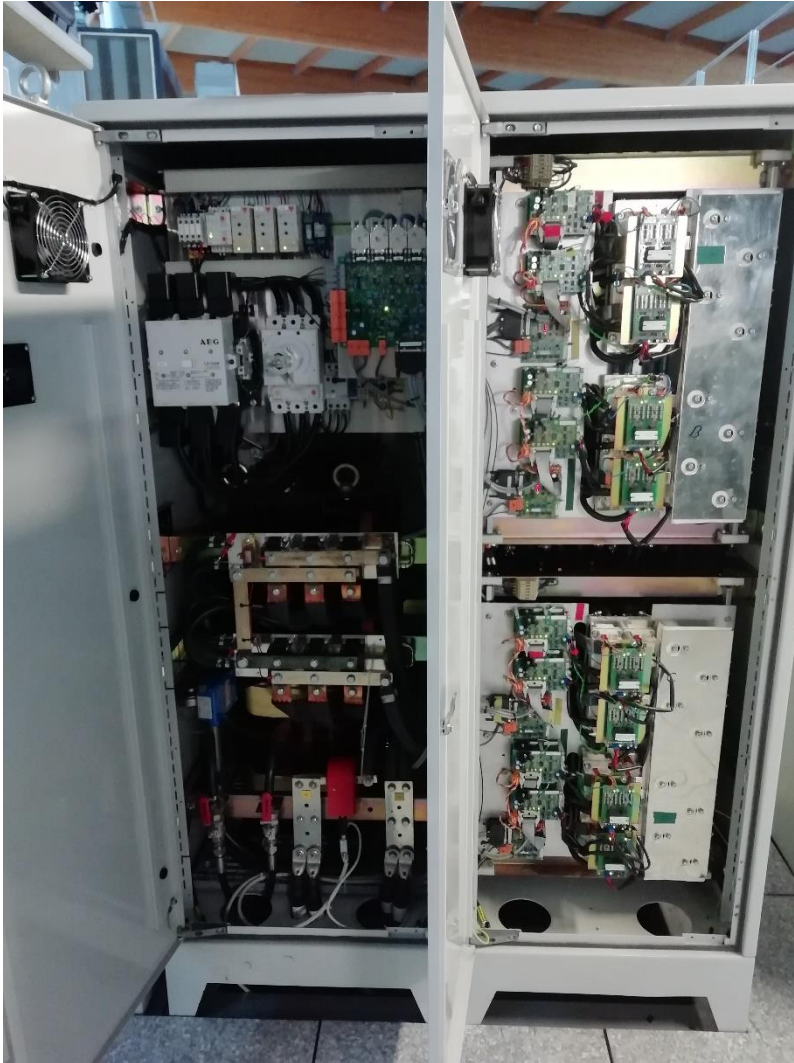
Cycle counters are now implemented on our 3Hz power supplies, to accurately follow the lifetime

- DANFYSIK power supplies: A continuous nightmare...



- Too compact
- Too complex
- Poor diagnostics (many interlocks in series \Rightarrow Identification of faulty element is difficult)
- DANFYSIK support: Ineffective (+ unaffordable)

- DANFYSIK power supplies: Overview since September 2022...



- **Many failures with the 859 family PS**
- Luckily, we only have 6 of these PS, which power electromagnetic undulators feeding the beamlines
- 9 (!) cards changed since September 2022
- Fortunately, nearly no impact on the beamlines, but many hours of investigation to solve all the problems

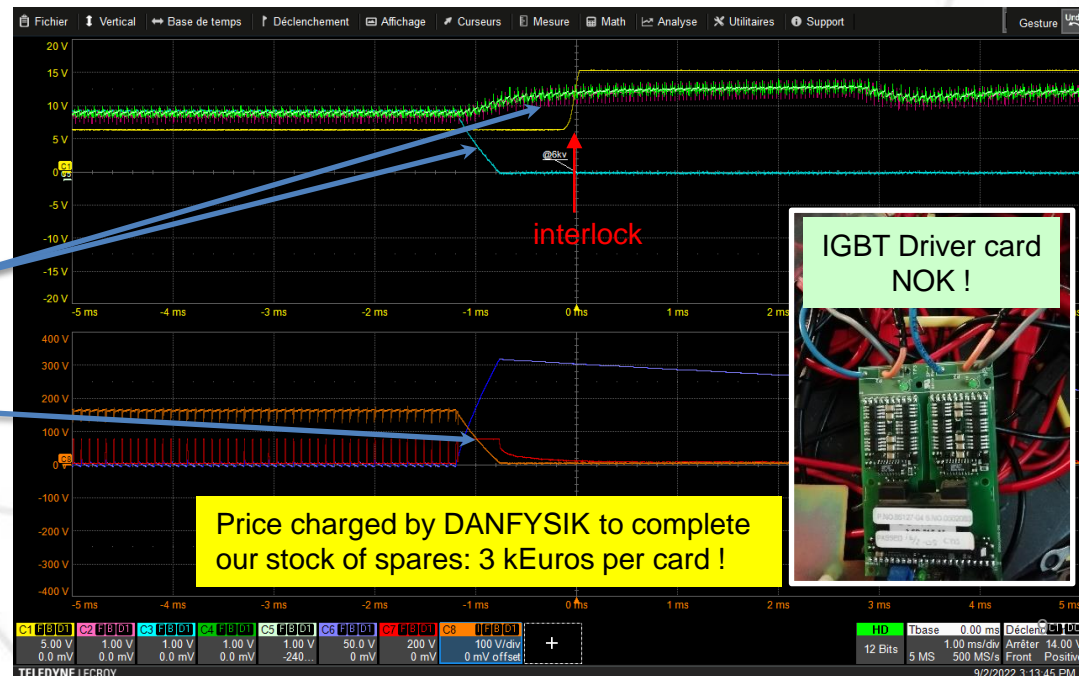
- **DANFYSIK power supplies: Some failures examples...**

- September 2022: **Sporadic “DC Overload” Faults**
- The “DC Overload” fault is a sum of many interlocks:
 - Overcurrent at the output of one of the 16 (!) IGBT legs
 - Overcurrent at the output of the power supply
 - Malfunction of one the 16 PCMPMW cards
 - Malfunction of one of the 4 PCMINT cards
 - All these interlocks are serialized on the FQDRINT and REGULATION MODULES SMD cards and are finally transmitted to the CONTROL BOARD for processing
- Where to start when the fault is not permanent ? Here, time and energy are requested...



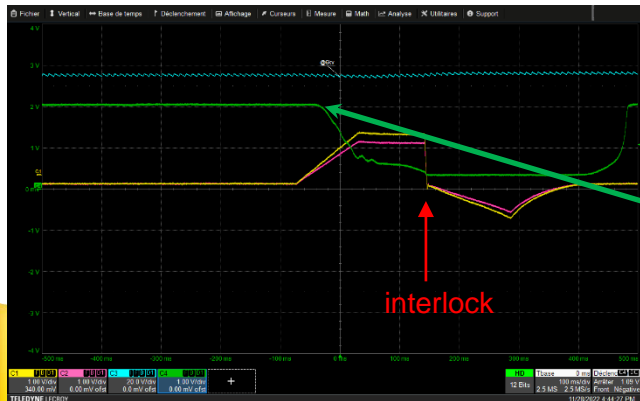
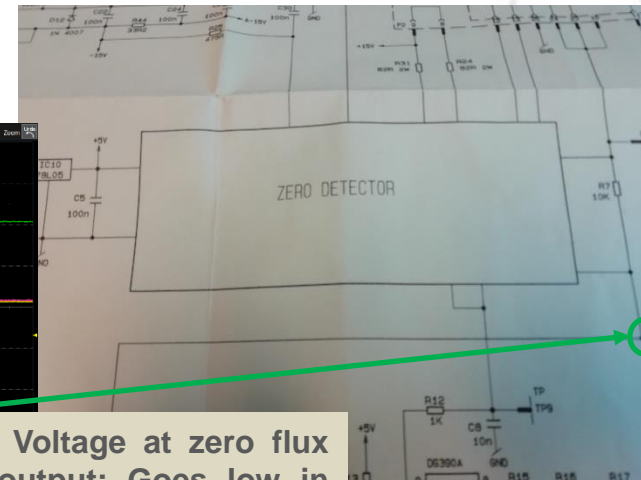
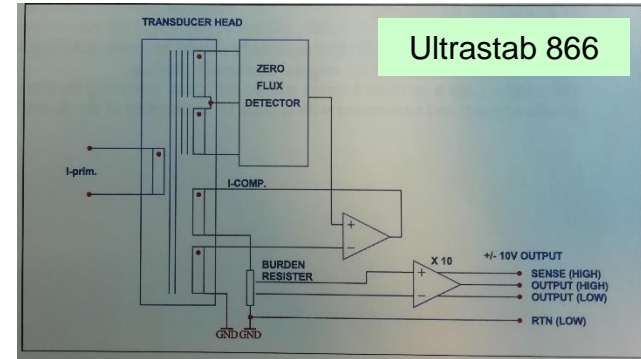
After many hours...

Output current of the IGBT legs
One IGBT is set and maintained OFF shortly before the interlock



- **DANFYSIK power supplies: Some failures examples...**


- November 2022: **“OCP” Fault** : Indicates a saturation of the DCCT zero detector cores (compensating winding of the DCCT is unable to cancel the ampere turns of the primary current)
- Phenomena only for negative currents, above a certain level of current
- Check of DCCT auxiliary power supplies: OK
- Replacement of DCCT head: No improvement
- Replacement of DCCT card: No improvement
- No schematic available of the zero detector circuitry



In green: Voltage at zero flux detector output: Goes low in case of saturation

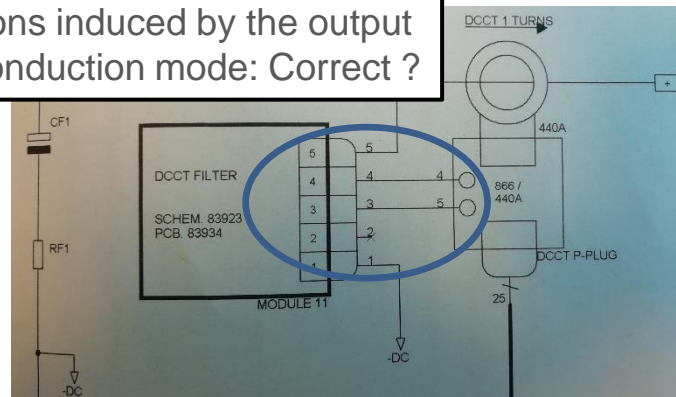
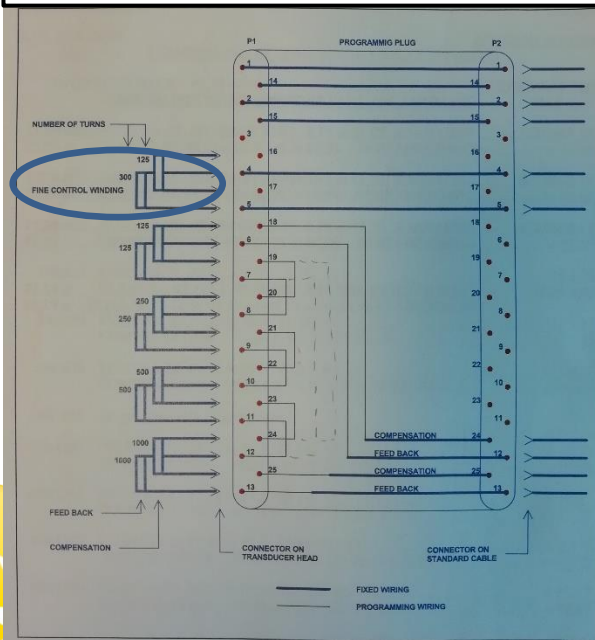
In yellow + red: Output current/voltage (opposite sign)

- DANFYSIK power supplies: Some failures examples...**

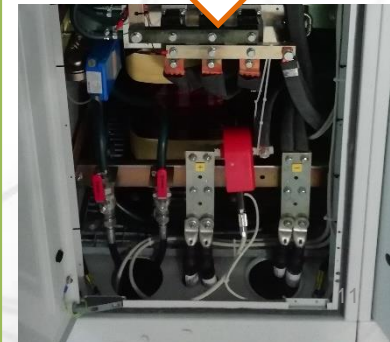
- November 2022: **“OCP” Fault**
- Decision to replace the DCCT (head + electronic card) with another DCCT reference  integrating the electronics (including zero flux detector circuitry)
 - ⇒ No improvement ; Worse: Huge output voltage oscillations, but only for low output current
 - ⇒ These power supplies cannot operate without the “Fine control winding” of the DCCT connected to the PS output potentials ⇒ ????



Seems to compensate the oscillations induced by the output stage operation in discontinuous conduction mode: Correct ?

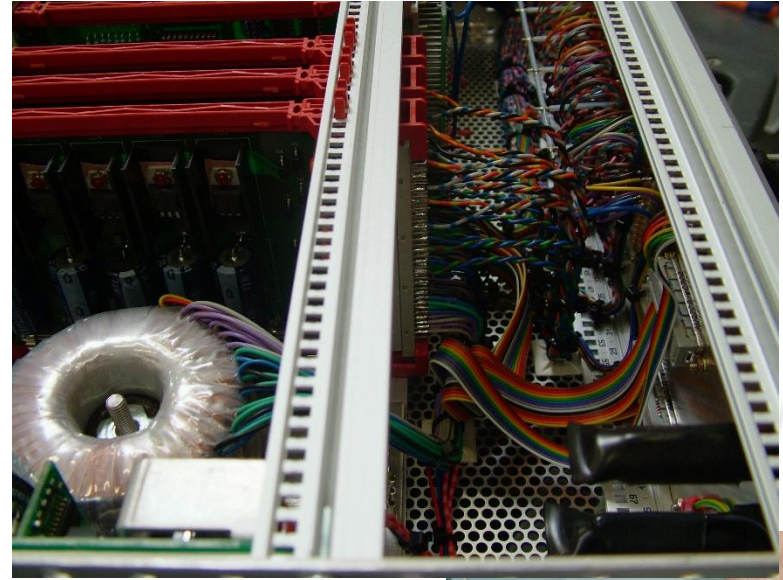
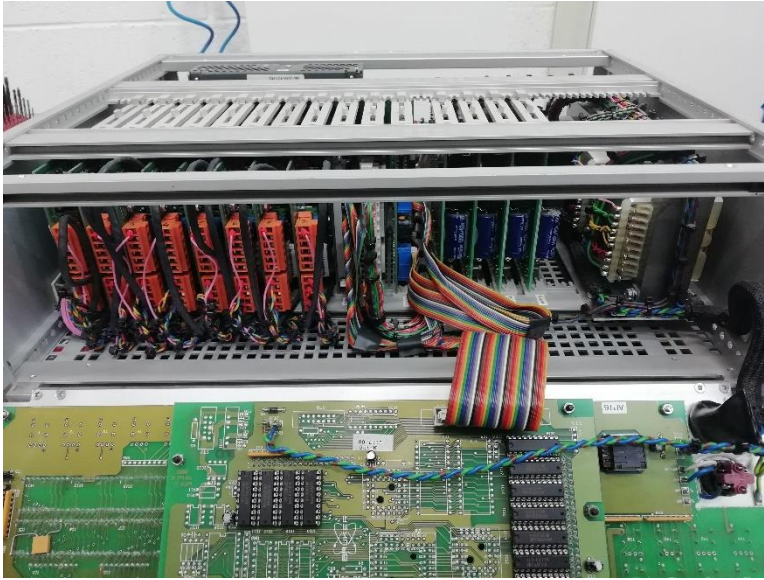


- General observation: DCCT head close to PS output inductors deep inside the rack
- **Problem solved by moving the DCCT head at the bottom of the rack, far from the initial location**
- Current ripple in the output filter inductors is OK: Emergence of this saturation of the DCCT (only for negative currents, after 15 years of operation) remains a mystery... Any ideas ?



Many other problems in 2023...
Situation is now stabilized (until when ?)

- Short focus on wiring/electrical connections

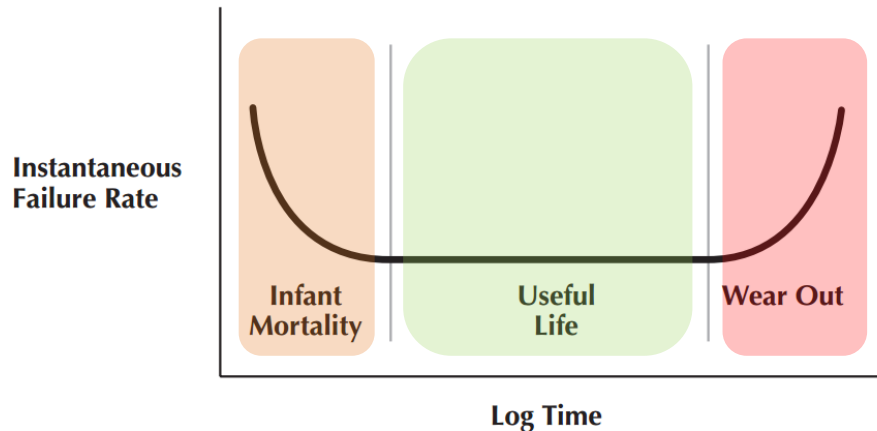


- No backplane cards in some of our power supply crates + lots of cabling/electrical connections
- **After 17 years of operation, reliability issues begin to appear**
- ⇒ **Such kind of design will be avoided for SOLEIL Upgrade**



Chosen strategy to enhance equipment reliability:

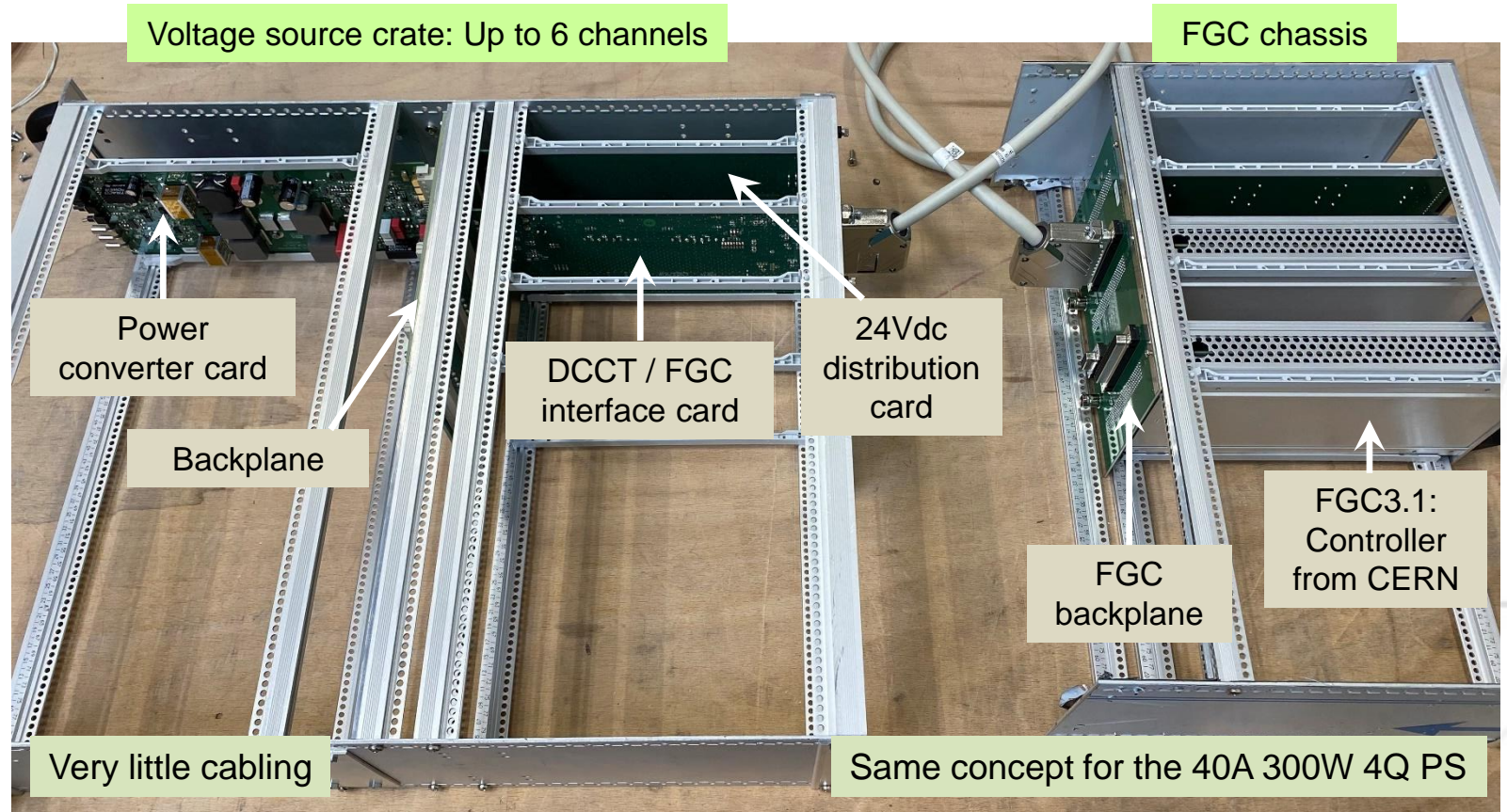
- Careful design
- Predict useful life failure rate \Rightarrow Software to calculate MTBF: iQT ITEM Software
- Improve overall robustness and lifetime
 - \Rightarrow HALT (Highly Accelerated Life Tests) on developed prototypes: More on this in the next slides
 - \Rightarrow Before the dark period in 2028: Tests of power supply prototypes on the existing machine under normal operating conditions to detect any potential anomaly
- High quality production: Pre-selection of suitable suppliers
- Remove infant mortality: Burn-in tests on all equipment prior to installation



Purchase of climatic chamber

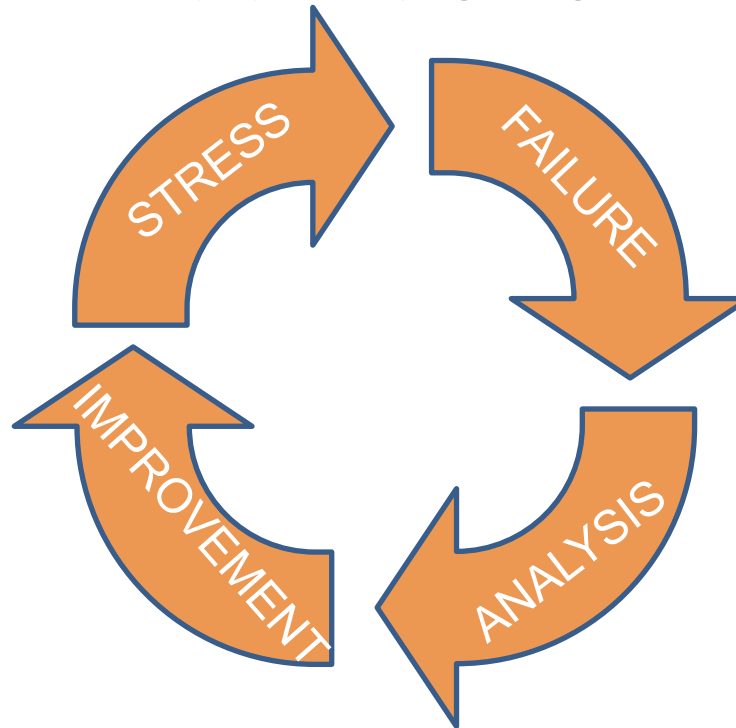


20A 100W 4Q power supply prototype for SOLEIL II:



- Focus on the **HALT** methodology:

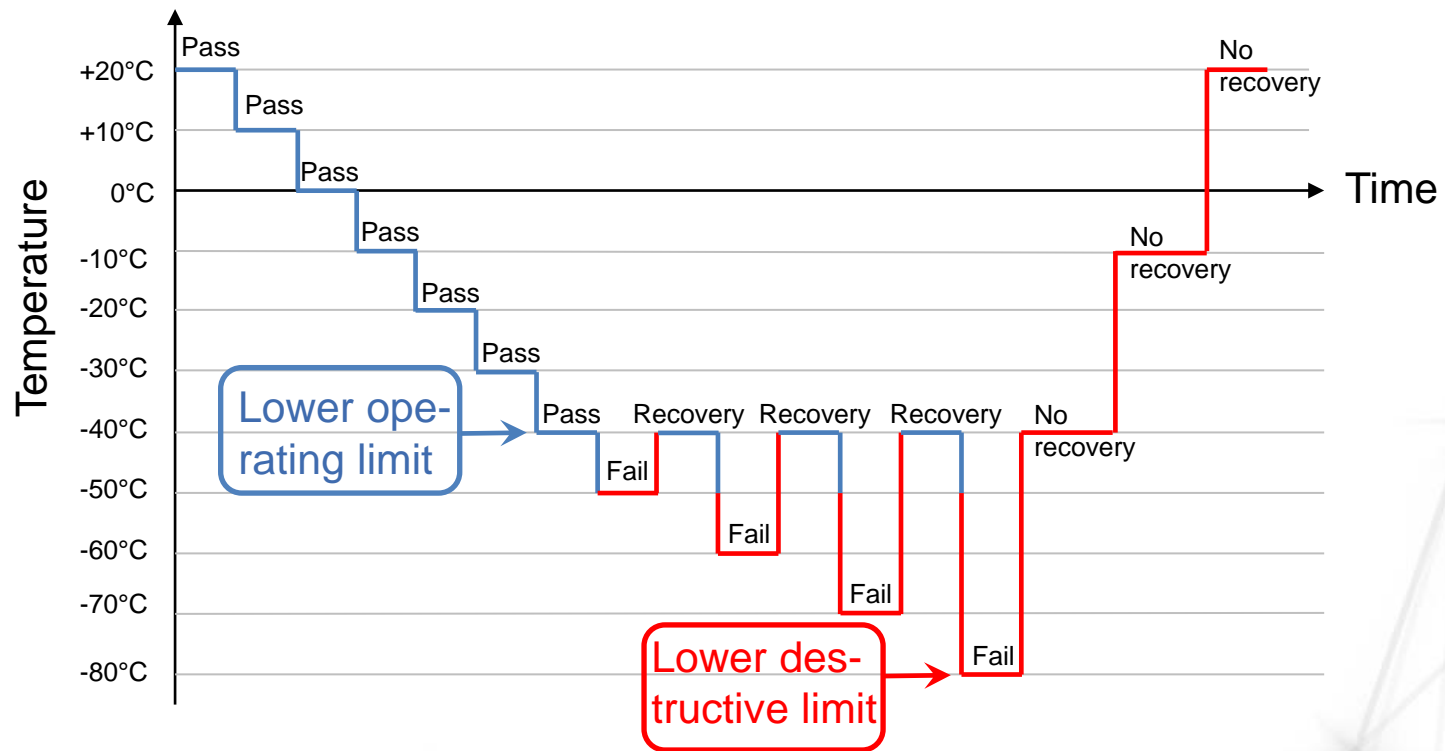
- **Highly Accelerated Life Test**
- Goal: Enhance product reliability by identifying design defects & weaknesses (R&D phase)
- **Principle:**



- No pre-established environmental stress limits: The robustness of the product determines the limits which can be significantly beyond those expected during normal use
- Thermal + mechanical stresses are applied until failure / destruction
- HALT gives you: Operating limits + destructive limits of the product
- Analysis of the failures allows you to build the robustness of your product

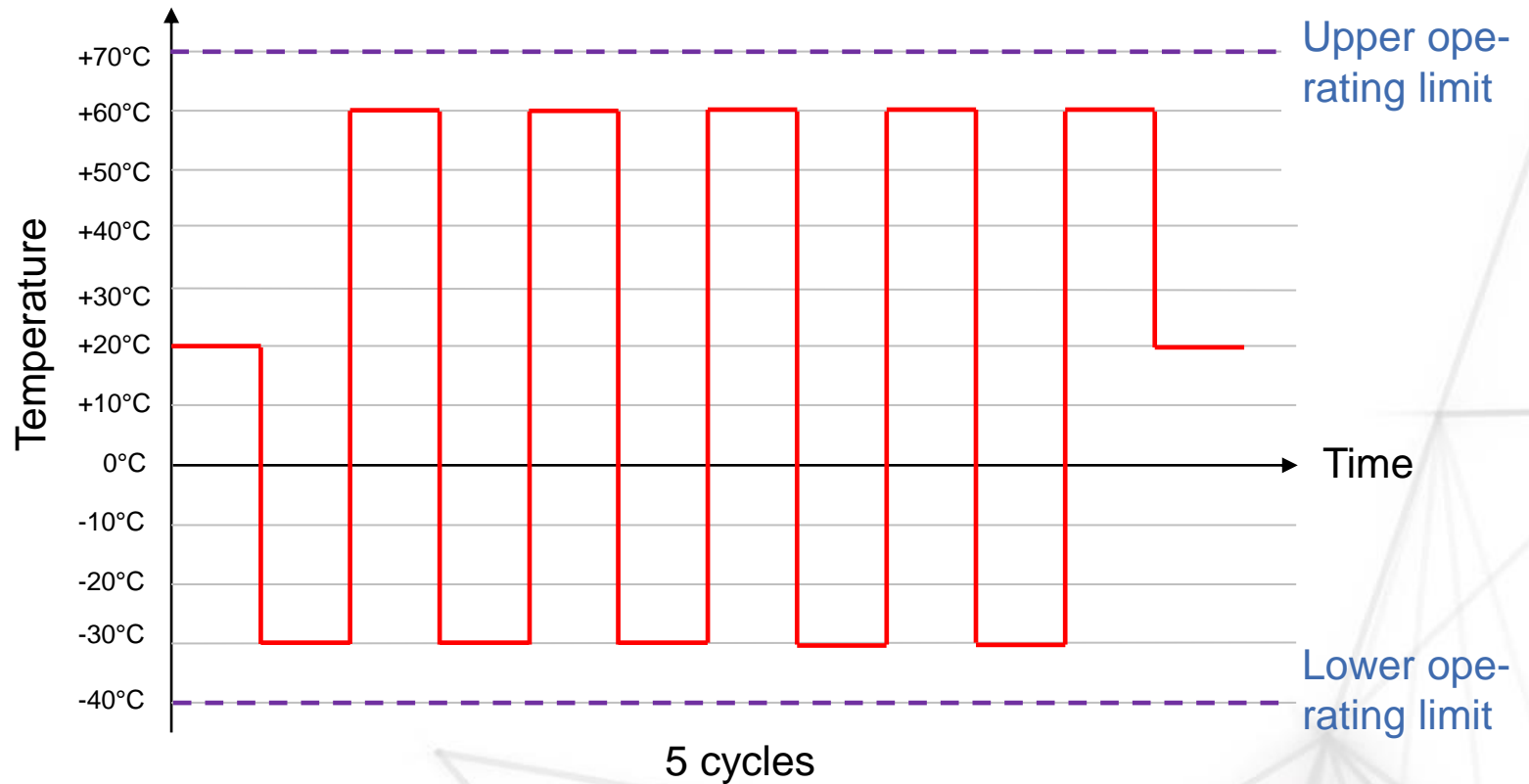
- Focus on the **HALT** methodology:

- Example: Step by step temperature decrease



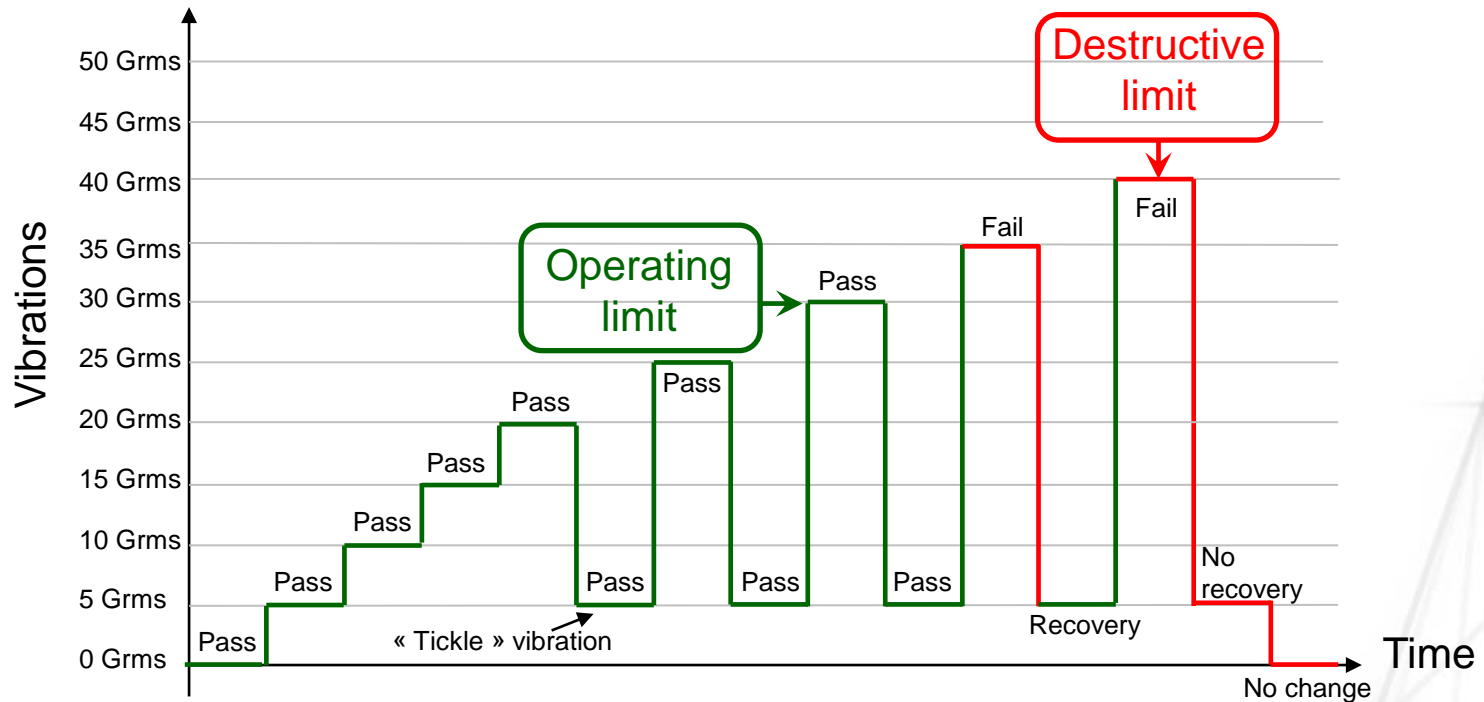
- Focus on the **HALT** methodology:

- Example: Rapid temperature variations (min. 45°C/min, up to 60°C/min)



- Focus on the **HALT** methodology:

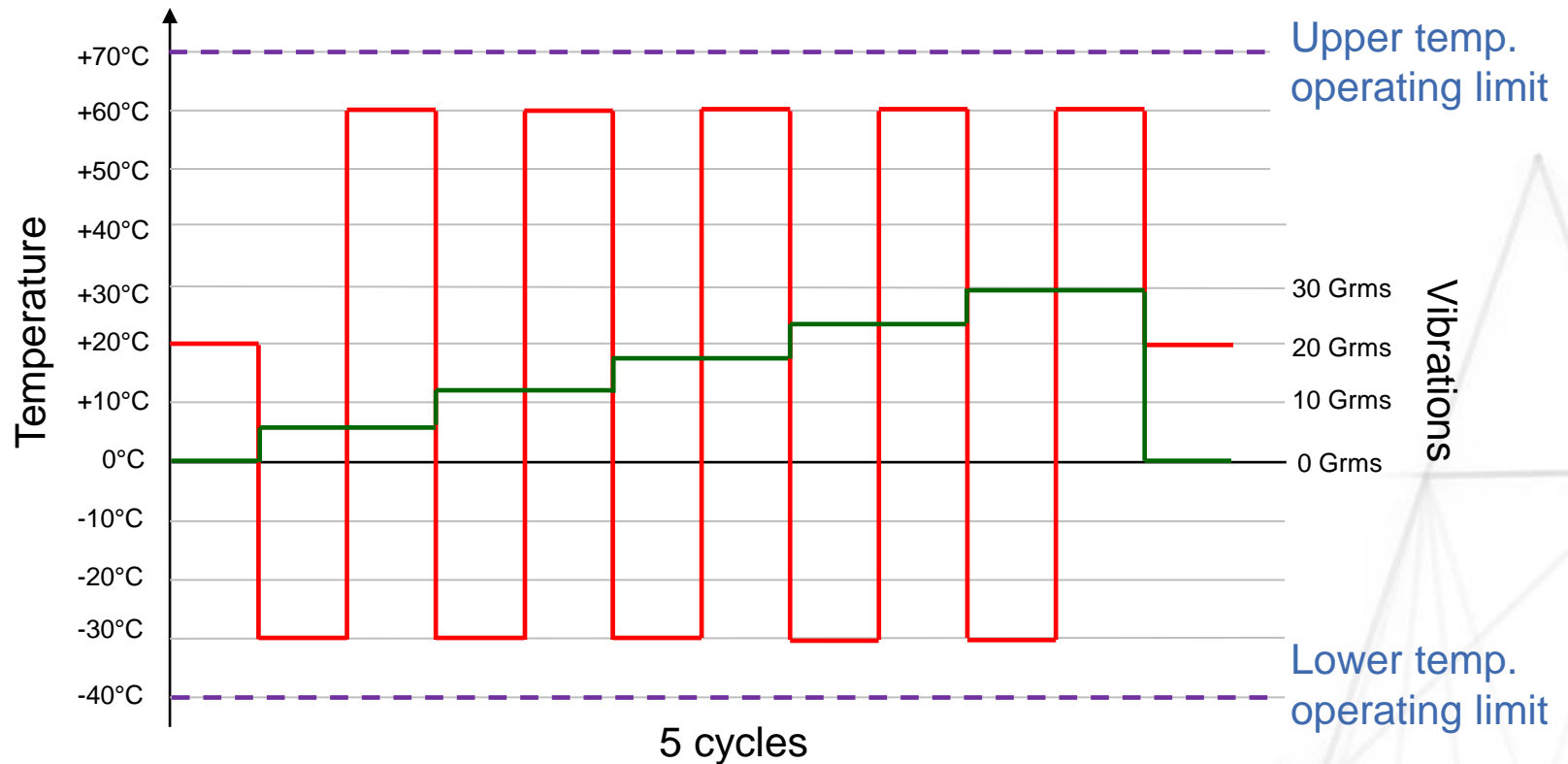
- Example: Step by step “Grms” vibration level increase



Pseudo-random vibrations 0 to 10 kHz on the 3 axes

- Focus on the **HALT** methodology:

- Example: Combined test RTV & vibration



HALT in short = **CRASH TEST**: Purpose is **not to simulate** an environment to check the proper functioning of an equipment, but **to stimulate a product** in order to know its limits + determine the root causes of all failures and corrective actions **to resolve the weak points** in the design (iterative process)
 ⇒ HALT is about to start on the developed prototypes for SOLEIL II

- **Power converter operation:** Availability is crucial [$A = \text{MTBF}/(\text{MTBF} + \text{MTTR})$]
- First years of operation of SOLEIL have been difficult: High failure rate
- Still some difficulties today (mainly with DANFYSIK systems)
- Design & construction of most of the existing power supplies completely outsourced
- Since 2007: A lot of redesign + maintenance operations + PS monitoring enhancement, before reaching good operation statistics
- **Different approach for SOLEIL II:**
 - Most power supplies designed in-house
 - Single controller for all the PS: FGC controller from CERN, with extensive self-diagnostic
 - Set up of a strategy to enhance reliability from the prototyping phase (\Rightarrow high MTBF)
 - Ease of repair / maintenance (\Rightarrow low MTTR)

Thank you for your attention

